Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/682,010	KEMPF, JEFFREY MATTHEW	
Examiner	**Art Unit**	
Kevin M. Nguyen	2629	

SEARCHED			
Class	Subclass	Date	Examiner
345	694-699, 618	5/18/2006	KMN
348	445,446		
382	260,266		
708	300,320		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Text and inventor search, see East notes printout.	5/18/2006	KMN